

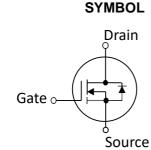
SPQ2RN30WPI

30V N-Channel MOSFET

- Advanced Split Gate Device Design and Processes
- High Reliability Capability

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• Sampled CP Probing and Inking



Electric	Electrical Characteristics in C/P Test (TJ at 25 °C)					
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
V _{(BR)DSS}	Drain-Source Breakdown Voltage	30		_	V	V _{GS} =0V, I _D =250µA
R _{DS(ON)}	Static Drain-Source On-Resistance		1.6	2	mΩ	$V_{GS} = 10V, I_{D} = 1A(1)$
R _{DS(ON)}	Static Drain-Source On-Resistance		1.8	2.2	mΩ	$V_{GS} = 4.5 V, I_D = 1 A^{(1)}$
V _{GS (th)}	Gate Threshold Voltage	1		2.5	V	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
I _{DSS}	Drain-to-Source Leakage Current	_	-	1	μA	V_{DS} =30V, V_{GS} =0V
I _{GSS}	Gate-to-Source Leakage Current	-100	4	100	nA	V_{DS} =0V, V_{GS} =±20V
T_J, T_{STG}	Operating and Storage Temperature	-55°C to 150°C Max.				

Mechanical Data	Die Drawing		
Chip Size ⁽²⁾	2174 µm X 1296 µm	1296.475 um	
Gate Pad Size	170 μm X 170 μm		
Source Pad Size(1)	1643µm X 1016µm	543 43	
Scribe Line Width	60 µm		
Wafer Thickness	100 µm		
Wafer Diameter	200 mm	2173.55	
Gross Die	9488 EA	3.55 um	
Source Metallization	Ti-NiV-Ag / 1-3-1.5kA		
Drain Metallization	Ti-Ni-Ag	1016.475 um	
Passivation	Polyimide		
Recommended Storage Environment	Store in original container, in dry nitrogen, 6 months at ambient temperature of 23°C ± 3°C	170um 170um	

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(1) Pulse Width tp = < 1 mS, Duty Cycle < 2%.

(2) Chip size not include scribe line.



Specific Assembly Info	Die Drawing	
Package Type	DFN5*6	1296.475 um
Die Attach Method	Soft solder	1643 um
Soft Solder Composition	Pb,Sn,Ag	
Gate Wire Bonding	Cu, 2 mil x1	2173.55 u
Source Wire Bonding	Cu, clip	З
Molding Compound Manufacturer	G700HF	1016.475 um
Solder Plating Composition	Pure Tin	170um

	Pos	ition	Bonding Diagram Top View
	X (μm)	Υ (μm)	тор
ZERO	0	0	52
ТОР	2173.55	1296.475	
S1	140	140	S1 G2
S2	1783	1156.475	
G1	1967	36.7	
G2	2137	206.7	



Electrical Characteristics in F/T Test (T_J at 25 °C)

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
I _{DSS}	Drain-to-Source Leakage Current	—	—	1	μA	V_{DS} =30V, V_{GS} =0V
I _{GSSF}	Gate-to-Source Leakage Current	_	_	100	nA	V _{DS} =0V, V _{GS} =+20V
I _{GSSR}	Gate-to-Source Leakage Current	-100	_	_	nA	V _{DS} =0V, V _{GS} =-20V
BV_{DSS}	Drain-Source Breakdown Voltage	30	_	_	V	V _{GS} =0V, I _D =250µA
BV_{DSS}	Drain-Source Breakdown Voltage	30		_	V	V_{GS} =0V, I_{D} =1mA
R _{DS(ON)}	Static Drain-Source On-Resistance			2.4	mΩ	$V_{GS} = 10V, I_{D} = 30A$
R _{DS(ON)}	Static Drain-Source On-Resistance	—	_	2.7	mΩ	V _{GS} =4.5V, I _D =20A
$V_{GS (th)}$	Gate Threshold Voltage	1	_	2.5	V	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
V_{SD}	Body Diode Forward Voltage	_	_	1.1	V	V _{GS} =0V, I _{SD} =10A
I _{AS}	Avalanche Current				A	V_{DD} =30V, V_{GS} =10V, R_{G} =25 Ω , L=0.5mH
T_{J}, T_{STG}	Operating and Storage Temperature	-55	—	150	°C	

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